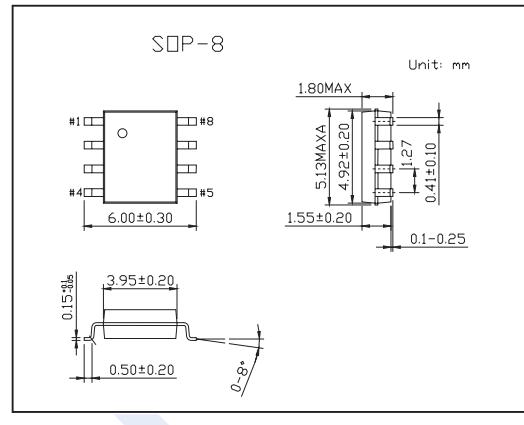
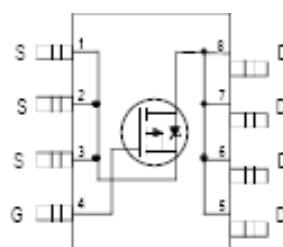


## HEXFET Power MOSFET

### KRF7205(IRF7205)

#### ■ Features

- Advanced Process Technology
- Ultra Low On-Resistance
- P-Channel MOSFET
- Surface Mount
- Dynamic dv/dt Rating
- Fast Switching



#### ■ Absolute Maximum Ratings Ta = 25°C

Parameter	Symbol	Rating	Unit
Continuous Drain Current, Vgs @ 10V @ TA = 25°C	Id	-4.6	A
Continuous Drain Current, Vgs @ 10V @ TA = 70°C	Id	-3.7	
Pulsed Drain Current *1	Idm	-15	
Power Dissipation @Tc = 25°C	Pd	2.5	W
Linear Derating Factor		0.02	V
Gate-to-Source Voltage	Vgs	±20	V
Peak Diode Recovery dv/dt *2	dv/dt	-3	V/ns
Maximum Junction-to-Ambient *3	Rθ JA	50	°C/W
Junction and Storage Temperature Range	Tj, Tstg	-55 to + 150	°C

\*1 Repetitive rating; pulse width limited by max. junction temperature.

\*2 Ids ≤ -4.6A, di/dt ≤ 90A/μs, VDD ≤ V(BR)DSS, TJ ≤ 150°C

\*3 Surface mounted on FR-4 board, t ≤ 10sec.

**KRF7205(IRF7205)**

## ■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Testconditons	Min	Typ	Max	Unit
Drain-to-Source Breakdown Voltage	V <sub>DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> = -250A	-30			V
Static Drain-to-Source On-Resistance	R <sub>D(on)</sub>	V <sub>GS</sub> = -10V, I <sub>D</sub> = -4.6A*1			0.070	Ω
		V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -2.0A*1			0.130	
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250 μ A	-1.0		-3.0	V
Forward Transconductance	g <sub>fs</sub>	V <sub>DS</sub> = -15V, I <sub>D</sub> = -4.6A*1		6.6		S
Drain-to-Source Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> = -24V, V <sub>GS</sub> = 0V			-1.0	μ A
		V <sub>DS</sub> = -16V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 70°C			-5.0	
Gate-to-Source Forward Leakage	I <sub>GSS</sub>	V <sub>GS</sub> = -20V			-100	nA
Gate-to-Source Reverse Leakage		V <sub>GS</sub> = 20V			100	
Total Gate Charge	Q <sub>g</sub>	I <sub>D</sub> = -4.6A		27	40	nC
Gate-to-Source Charge	Q <sub>gs</sub>	V <sub>DS</sub> = -15V		5.2		
Gate-to-Drain ("Miller") Charge	Q <sub>gd</sub>	V <sub>GS</sub> = -10V,*1		7.5		
Turn-On Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> = -15V		14	30	ns
Rise Time	t <sub>r</sub>	I <sub>D</sub> = -1.0A		21	60	
Turn-Off Delay Time	t <sub>d(off)</sub>	R <sub>G</sub> = 6.0 Ω		97	150	
Fall Time	t <sub>f</sub>	R <sub>D</sub> = 10 Ω *1		71	100	
Internal Source Inductance	L <sub>s</sub>	Between lead, 6mm(0.25in.) from package and center of die contact		2.5		nH
Internal Drain Inductance	L <sub>d</sub>			4.0		
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0V		870		pF
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> = -10V		720		
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1.0MHz		220		
Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25°C, I <sub>F</sub> = -4.6A di/dt = 100A/ μ s*1		70	100	ns
Reverse Recovery Charge	Q <sub>rr</sub>			100	180	nC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>s</sub> +L <sub>d</sub> )				
Continuous Source Current (Body Diode)	I <sub>s</sub>	MOSFET symbol showing the integral reverse p-n junction diode.			-2.5	A
Pulsed Source Current (Body Diode) *2	I <sub>SM</sub>				-15	
Diode Forward Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25°C, I <sub>s</sub> = -1.25A, V <sub>GS</sub> = 0V*1			-1.2	V

\*1 Pulse width ≤ 300 μ s; duty cycle ≤ 2%.

\*2 Repetitive rating; pulse width limited bymax